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億光電子工業股份有限公司 EVERLIGHT ELECTRONICS CO., LTD. 台北縣土城市中央路三段76巷25號

NO. 25, LANE 76, SEC. 3, CHUNG YANG ROAD, TUCHENG, TAIPEI, TAIWAN, R. O. C.

## 以下測試樣品係由客户送樣,且由客户聲稱並經客户確認如下 (The following samples was/were submitted and identified by/on behalf of the client as):

BASIC INFORMATION				
Type of Product	SMD 45/50 SERIES			
Supplier Company Name	EVERLIGHT			
Address	NO. 25, LANE 76, SEC. 3, CHUNG YANG ROAD, TUCHENG, TAIWAN, R. O. C.			
Tel/Fax/Email	TEL:886-2-267-2000 EXT:1203			
	FAX:886-2-267-9948			
	E-MAIL: meelin@everlight.com			
Contact Person	LIN HSIAO HUA			
EVERLIGHT REPORT NO	EVERLIGHT-45-11UNC / TR8 -SGS-03/02/2010			
PRODUCT INFORMATION				
Product/component Sample description	BACK LIGHT			
Quantity (numbers or weight)	0.0155 g			
EVERLIGHT P/N	45-11UNC / TR8			
Product Lot No	Y100118H1603FJ-K-C-EX-R			
Country of Origin	TAIWAN			
TEST INFORMATION				
Digital Photo(s) of sample(s) after being	JPG EMBEDDED IN EACH REPORT			
prepared				
Sample preparation	CUTTING			
Test Method	Cd , Pb , Hg , Cr(VI), PBB/PBDE - IEC 62321, Halogen-BS EN 14582			
PQL and/or MDL	Cd , Pb , Hg: < 2 mg/kg; PBB/PBDE: < 5 mg/kg; Halogen: 50 mg/kg			
Name of Analyzer	Cd , Pb , Hg, Cr(VI): Climbgreat Yang;			
	PBB/PBDE: Roman Wong; Halogen: Alan Chen			
If All and the Co. In the Co.				

收件日期(Sample Receiving Date)

: 2010/01/28

測試期間(Testing Period)

2010/01/28 TO 2010/02/03

\_\_\_\_\_\_

測試結果(Test Results)

請見下一頁 (Please refer to next pages).

Chenyu Kung / Operation Manager Signed for and on behalf of SGS TAIWAN LTD.

Chemical Laboratory - Taipei

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#### 測試結果(Test Results)

測試部位(PART NAME) NO.1 : SMD 45/50 SERIES 一般用

測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限値 (MDL)	結果 (Result) NO.1
鎬 / Cadmium (Cd)	mg/kg	参考IEC 62321: 2008方法,以感應藕 合電漿原子發射光譜儀檢測. / With reference to IEC 62321: 2008 and performed by ICP-AES.	2	n.d.
鉛 / Lead (Pb)	mg/kg	參考IEC 62321: 2008方法, 以感應藕 合電漿原子發射光譜儀檢測. / With reference to IEC 62321: 2008 and performed by ICP-AES.	2	n.d.
汞 / Mercury (Hg)	mg/kg	参考IEC 62321: 2008方法,以感應藕 合電漿原子發射光譜儀檢測. / With reference to IEC 62321: 2008 and performed by ICP-AES.	2	n.d.
六價鉻 / Hexavalent Chromium Cr(VI) by alkaline extraction	mg/kg	參考IEC 62321: 2008方法,以UV-VIS 檢測. / With reference to IEC 62321: 2008 and performed by UV- VIS.	2	n.d.
全氟辛烷磺酸 / Perfluorooctane sulfonates (PFOS) PFOS — Acid PFOS — Metal Salt PFOS — Amide	mg/kg	参考US EPA 3540C: 1996方法,以液相層析質譜儀檢測全氟辛烷磺酸含量./ With reference to US EPA 3540C: 1996 method for PFOS Content. Analysis was performed by LC/MS.	10	n.d.
全氟辛酸(銨) / PFOA (CAS No.: 000335-67-1)	mg/kg	参考US EPA 3540C: 1996方法,以液相層析質譜儀檢測全氟辛酸(銨)含量./ With reference to US EPA 3540C: 1996 method for PFOA Content. Analysis was performed by LC/MS.	10	n.d.

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測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限値 (MDL)	結果 (Result) NO.1
四溴雙酚-A / Tetrabromobisphenol A (TBBP-A) (CAS No.: 000079-94-7)	mg/kg	参考DIN 53313方法,以氣相層析儀/質 譜儀檢測. / With reference to DIN 53313 method. Analysis was performed by GC/MS.	10	n.d.
多溴聯苯總和 / Sum of PBBs			-	n.d.
一溴聯苯 / Monobromobiphenyl			5	n.d.
二溴聯苯 / Dibromobiphenyl			5	n.d.
三溴聯苯 / Tribromobiphenyl			5	n.d.
四溴聯苯 / Tetrabromobiphenyl			5	n.d.
五溴聯苯 / Pentabromobiphenyl			5	n.d.
六溴聯苯 / Hexabromobiphenyl		參考IEC 62321: 2008方法,以氣相層 析儀/質譜儀檢測. / With reference	5	n.d.
七溴聯苯 / Heptabromobiphenyl			5	n.d.
八溴聯苯 / Octabromobiphenyl			5	n.d.
九溴聯苯 / Nonabromobiphenyl			5	n.d.
十溴聯苯 / Decabromobiphenyl	/1		5	n.d.
多溴聯苯醚總和 / Sum of PBDEs	mg/kg	to IEC 62321: 2008 and performed	-	n.d.
一溴聯苯醚 / Monobromodiphenyl ether		by GC/MS.	5	n.d.
二溴聯苯醚 / Dibromodiphenyl ether			5	n.d.
三溴聯苯醚 / Tribromodiphenyl ether			5	n.d.
四溴聯苯醚 / Tetrabromodiphenyl ether			5	n.d.
五溴聯苯醚 / Pentabromodiphenyl ether			5	n.d.
六溴聯苯醚 / Hexabromodiphenyl ether			5	n.d.
七溴聯苯醚 / Heptabromodiphenyl ether			5	n.d.
八溴聯苯醚 / Octabromodiphenyl ether			5	n.d.
九溴聯苯醚 / Nonabromodiphenyl ether			5	n.d.
十溴聯苯醚 / Decabromodiphenyl ether			5	n.d.

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測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限値 (MDL)	結果 (Result) NO.1
鹵素 / Halogen				
鹵素(氟)/ Halogen-Fluorine (F) (CAS No.: 014762-94-8)	mg/kg	参考BS EN 14582:2007, 以離子層析儀 分析. / With reference to BS EN 14582:2007. Analysis was performed by IC.	50	n.d.
鹵素(氣)/ Halogen-Chlorine (C1) (CAS No.: 022537-15-1)	mg/kg	参考BS EN 14582:2007, 以離子層析儀 分析. / With reference to BS EN 14582:2007. Analysis was performed by IC.		n.d.
鹵素(溴)/ Halogen-Bromine (Br) (CAS No.: 010097-32-2)	mg/kg	参考BS EN 14582:2007, 以離子層析儀 分析. / With reference to BS EN 14582:2007. Analysis was performed by IC.	50	n.d.
鹵素(碘)/ Halogen-Iodine (I) (CAS No.: 014362-44-8)	mg/kg	参考BS EN 14582:2007, 以離子層析儀 分析. / With reference to BS EN 14582:2007. Analysis was performed by IC.	50	n.d.

#### 備註(Note):

- 1. mg/kg = ppm ; 0.1wt% = 1000ppm
- 2. n.d. = Not Detected (未檢出)
- 3. MDL = Method Detection Limit (方法偵測極限值)
- 4. "-" = Not Regulated (無規格值)

#### PFOS参考資訊(Reference Information): 指令 2006/122/EC (Directive 2006/122/EC)

- (1) 該物質不可置於市場上或使用於特殊物質或配置成分重量濃度等於或大於0.005%. (May not be placed on the market or used as a substance or constituent of preparations in a concentration equal to or higher than 0.005 % by mass.)
- (2) 該物質不可置於市場上的半成品或商品或其物件;假若零件上明顯地具有PFOS並參照結構上及微細構造上計算 PFOS重量濃度等於或大於0.1%, 而紡織品或其他覆蓋物質, 如果PFOS在覆蓋物質中含量等於或大於1µg/m². (May not be placed on the market in semi-finished products or articles, or parts thereof, if the concentration of PFOS is equal to or higher than 0.1 % by mass calculated with reference to the mass of structurally or microstructurally distinct parts that contain PFOS or, for textiles or other coated materials, if the amount of PFOS is equal to or higher than  $l\mu g/m^2$  of the coated material.)

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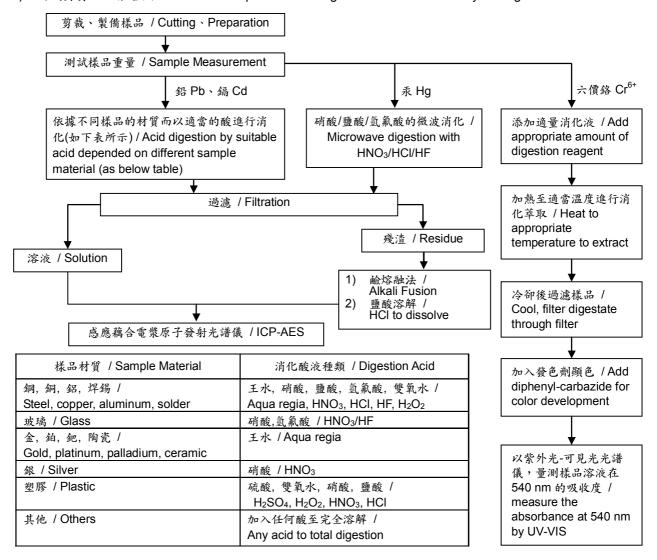
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- 1) 根據以下的流程圖之條件,樣品已完全溶解。( 六價鉻測試方法除外 ) / These samples were dissolved totally by pre-conditioning method according to below flow chart. ( $Cr^{6+}$  test method excluded)
- 2) 測試人員:楊登偉 / Name of the person who made measurement: Climbgreat Yang
- 3) 測試負責人:張啓興 / Name of the person in charge of measurement: Troy Chang



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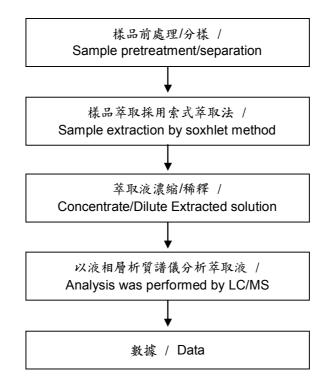
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## 索式萃取(LC/MS)分析流程圖 /

## Analytical flow chart of Soxhlet extraction (LC/MS) procedure

- 1) 測試人員:傅莉雅 / Name of the person who made measurement: Lydia Fu
- 2) 測試負責人: 陳新智 / Name of the person in charge of measurement: Shinjyh Chen
- 測試項目(Test Items): 全氟辛烷磺酸/全氟辛酸(銨)、苯並三唑類化合物 / PFOS/PFOA、Benzotriazole



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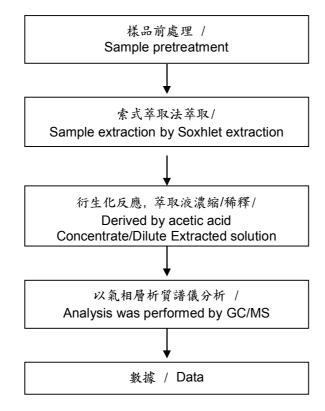
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# 分析流程圖 / analytical flow chart

- 1) 測試人員: 傅舒萱 / Name of the person who made measurement: Amanda Fu
- 2) 測試負責人: 陳新智 / Name of the person in charge of measurement: Shinjyh Chen
  - 測試項目(Test Items):四溴雙酚-A、雙酚 A/TBBP-A、Bisphenol A



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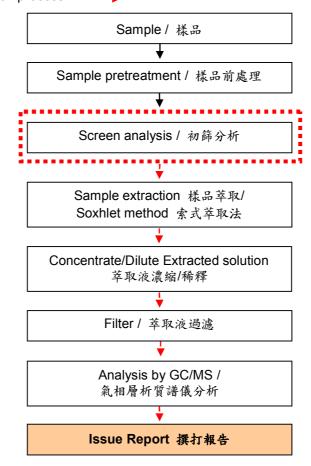
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## 多溴聯苯/多溴聯苯醚分析流程圖 / PBB/PBDE analytical FLOW CHART

- 1) 測試人員: 翁賜彬 / Name of the person who made measurement: Roman Wong
- 2) 測試負責人: 陳新智 / Name of the person in charge of measurement: Shinjyh Chen 初次測試程序 / First testing process ———▶

選擇性篩檢程序 / Optional screen process .......

確認程序 / Confirmation process \_ . \_ ▶



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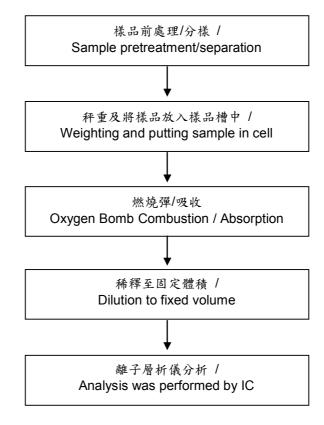
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## 鹵素分析流程圖 / Analytical flow chart of halogen content

- 1) 測試人員: 陳立倫 / Name of the person who made measurement: Alan Chen
- 2) 測試負責人:張啓興 / Name of the person in charge of measurement: Troy Chang



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\*\* 報告結尾(End of Report) \*\*

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